## Application/Control No: Applicant(s)/Patent Under Reexamination GREIL ET AL. Examiner Mark L. Berch Applicant(s)/Patent Under Reexamination GREIL ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,489,470	12-2002	Greil et al.	540/220
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 200134611 A1	05-2001	World Intellect	CHANG et al.	C07D501/36
	0	WO 200109143 A1	02-2001	World Intellect	ARORA et al.	C07D 00/00
	Р	JP 03031286 A	02-1991	Japan	HASHIMOTO et al.	C07D501/04
	Q					
	R					
	s	,				
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.